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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	37200
Number of Logic Elements/Cells	476160
Total RAM Bits	39223296
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vsx475t-1ff1156i

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I _{CCOQ}	Quiescent V _{CCO} supply current	XC6VLX75T	1	1	1	N/A	1	1	mA
		XC6VLX130T	1	1	1	N/A	1	1	mA
		XC6VLX195T	1	1	1	N/A	1	1	mA
		XC6VLX240T	2	2	2	N/A	2	2	mA
		XC6VLX365T	2	2	2	N/A	2	2	mA
		XC6VLX550T ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VLX760 ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VSX315T	2	2	2	N/A	2	2	mA
		XC6VSX475T ⁽³⁾	N/A	2	2	N/A	2	2	mA
		XC6VHX250T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX255T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	2	2	2	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	2	2	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1	N/A	1	N/A	1	mA
		XQ6VLX240T	N/A	2	N/A	2	N/A	2	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	3	N/A	3	mA
		XQ6VSX315T	N/A	2	N/A	2	N/A	2	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	2	N/A	2	mA

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	XC6VLX75T	45	45	45	N/A	45	45	mA
		XC6VLX130T	75	75	75	N/A	75	75	mA
		XC6VLX195T	113	113	113	N/A	113	113	mA
		XC6VLX240T	135	135	135	N/A	135	135	mA
		XC6VLX365T	191	191	191	N/A	191	191	mA
		XC6VLX550T ⁽³⁾	N/A	286	286	N/A	286	286	mA
		XC6VLX760 ⁽³⁾	N/A	387	387	N/A	387	387	mA
		XC6VSX315T	186	186	186	N/A	186	186	mA
		XC6VSX475T ⁽³⁾	N/A	279	279	N/A	279	279	mA
		XC6VHX250T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX255T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	227	227	227	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	315	315	N/A	N/A	N/A	mA
		XQ6VLX130T ⁽⁶⁾	N/A	75	N/A	75	N/A	75	mA
		XQ6VLX240T ⁽⁶⁾	N/A	135	N/A	135	N/A	135	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	286	N/A	286	mA
		XQ6VSX315T ⁽⁶⁾	N/A	186	N/A	186	N/A	186	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	279	N/A	279	mA

Notes:

- Typical values are specified at nominal voltage, 85°C junction temperatures (T_j). -1 and -2 industrial (I) grade devices have the same typical values as commercial (C) grade devices at 85°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. -1L industrial temperature range devices have the values specified in this column.
- Use the XPE tool to calculate 125°C values for -1M temperature range devices.
- The -2E extended temperature range (T_j = 0°C to +100°C) is only available in these devices. The -2I temperature range (T_j = -40°C to +100°C) is available for all other devices except the XC6VHX565T.
- The XC6VHX380T is available with both -2E and -2I temperature ranges.
- The XC6VHX565T is only available in the following temperature ranges: -1C, -1I, -2C, and -2E.
- The XQ6VLX130T, XQ6VLX240T, and XQ6VSX315T are available in -2I, -1I, -1M, and -1LI temperature ranges.
- The XQ6VLX550T and the XQ6VSX475T are only available in -1I and -1LI temperature ranges.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- If DCI or differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPE or XPower Analyzer (XPA) tools.

Table 6: Power Supply Ramp Time

Symbol	Description	Ramp Time	Units
V_{CCINT}	Internal supply voltage relative to GND	0.20 to 50.0	ms
V_{CCO}	Output drivers supply voltage relative to GND	0.20 to 50.0	ms
V_{CCAUX}	Auxiliary supply voltage relative to GND	0.20 to 50.0	ms

SelectIO™ DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 7: SelectIO DC Input and Output Levels

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVC MOS25, LVDCI25	-0.3	0.7	1.7	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	Note(3)	Note(3)
LVC MOS18, LVDCI18	-0.3	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.3$	0.45	$V_{CCO} - 0.45$	Note(4)	Note(4)
LVC MOS15, LVDCI15	-0.3	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.3$	25% V_{CCO}	75% V_{CCO}	Note(4)	Note(4)
LVC MOS12	-0.3	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.3$	25% V_{CCO}	75% V_{CCO}	Note(5)	Note(5)
HSTL I ₁₂	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	25% V_{CCO}	75% V_{CCO}	6.3	6.3
HSTL I ⁽²⁾	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	8	-8
HSTL II ⁽²⁾	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	16	-16
HSTL III ⁽²⁾	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	0.4	$V_{CCO} - 0.4$	24	-8
DIFF HSTL I ⁽²⁾	-0.3	50% $V_{CCO} - 0.1$	50% $V_{CCO} + 0.1$	$V_{CCO} + 0.3$	—	—	—	—
DIFF HSTL II ⁽²⁾	-0.3	50% $V_{CCO} - 0.1$	50% $V_{CCO} + 0.1$	$V_{CCO} + 0.3$	—	—	—	—
SSTL2 I	-0.3	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$V_{CCO} + 0.3$	$V_{TT} - 0.61$	$V_{TT} + 0.61$	8.1	-8.1
SSTL2 II	-0.3	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$V_{CCO} + 0.3$	$V_{TT} - 0.81$	$V_{TT} + 0.81$	16.2	-16.2
DIFF SSTL2 I	-0.3	50% $V_{CCO} - 0.15$	50% $V_{CCO} + 0.15$	$V_{CCO} + 0.3$	—	—	—	—
DIFF SSTL2 II	-0.3	50% $V_{CCO} - 0.15$	50% $V_{CCO} + 0.15$	$V_{CCO} + 0.3$	—	—	—	—
SSTL18 I	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.3$	$V_{TT} - 0.47$	$V_{TT} + 0.47$	6.7	-6.7
SSTL18 II	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.3$	$V_{TT} - 0.60$	$V_{TT} + 0.60$	13.4	-13.4
DIFF SSTL18 I	-0.3	50% $V_{CCO} - 0.125$	50% $V_{CCO} + 0.125$	$V_{CCO} + 0.3$	—	—	—	—
DIFF SSTL18 II	-0.3	50% $V_{CCO} - 0.125$	50% $V_{CCO} + 0.125$	$V_{CCO} + 0.3$	—	—	—	—
SSTL15	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	$V_{CCO} + 0.3$	$V_{TT} - 0.175$	$V_{TT} + 0.175$	14.3	14.3

Notes:

1. Tested according to relevant specifications.
2. Applies to both 1.5V and 1.8V HSTL.
3. Using drive strengths of 2, 4, 6, 8, 12, 16, or 24 mA.
4. Using drive strengths of 2, 4, 6, 8, 12, or 16 mA.
5. Supported drive strengths of 2, 4, 6, or 8 mA.
6. For detailed interface specific DC voltage levels, see [UG361](#): Virtex-6 FPGA SelectIO Resources User Guide.

HT DC Specifications (HT_25)

Table 8: HT DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		-15	—	15	mV
V_{OCM}	Output Common Mode Voltage	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		-15	—	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		-15	—	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		-15	—	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	—	—	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.825	—	—	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: Extended LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	—	—	1.785	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.715	—	—	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	350	—	840	mV
	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High for XQ devices		350	—	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	—	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.3	1.2	2.2	V

Table 16: GTX Transceiver Quiescent Supply Current (per Lane) ⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Typ ⁽⁴⁾	Max	Units
$I_{\text{MGTA VTTQ}}$	Quiescent MGTA VTT supply current for one GTX transceiver	0.9	Note 2	mA
$I_{\text{MGTA VCCQ}}$	Quiescent MGTA VCC supply current for one GTX transceiver	3.5		mA

Notes:

1. Device powered and unconfigured.
2. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.
3. GTX transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTX transceivers.
4. Typical values are specified at nominal voltage, 25°C.

GTX Transceiver DC Input and Output Levels

Table 17 summarizes the DC output specifications of the GTX transceivers in Virtex-6 FPGAs. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 17: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPIN}	Differential peak-to-peak input voltage	External AC coupled ≤ 4.25 Gb/s	125	–	2000	mV
		External AC coupled > 4.25 Gb/s	175	–	2000	mV
V_{IN}	Absolute input voltage	DC coupled MGTA VTT = 1.2V	–400	–	MGTA VTT	mV
V_{CMIN}	Common mode input voltage	DC coupled MGTA VTT = 1.2V	–	2/3 MGTA VTT	–	mV
DV_{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	–	–	1000	mV
V_{CMOUTDC}	DC common mode output voltage.	Equation based	$\text{MGTA VTT} - DV_{\text{PPOUT}}/4$			mV
R_{IN}	Differential input resistance		80	100	130	Ω
R_{OUT}	Differential output resistance		80	100	120	Ω
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	8	ps
C_{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

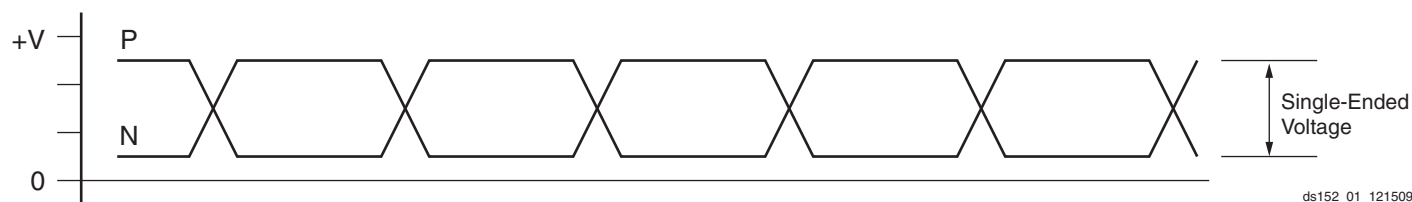


Figure 1: Single-Ended Peak-to-Ppeak Voltage

Table 21: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		62.5	–	650	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	1	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	200	μ s

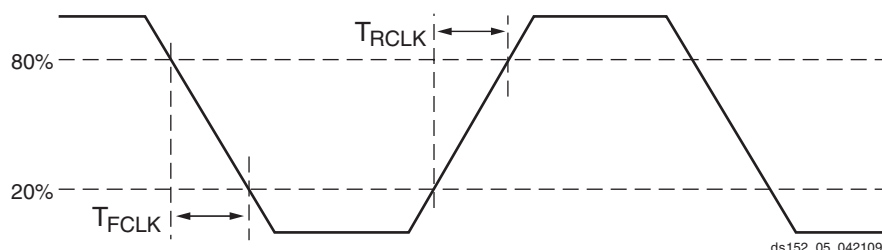


Figure 3: Reference Clock Timing Parameters

Table 22: GTX Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Conditions	Speed Grade				Units
			-3	-2	-1	-1L	
F_{TXOUT}	TXOUTCLK maximum frequency	Internal 20-bit data path	330	330	250	250	MHz
		Internal 16-bit data path	412.5	412.5	312.5	250	MHz
F_{RXREC}	RXRECCLK maximum frequency	Internal 20-bit data path	330	330	250	250	MHz
		Internal 16-bit data path	412.5	412.5	312.5	250	MHz
T_{RX}	RXUSRCLK maximum frequency		412.5 ⁽²⁾	412.5 ⁽²⁾	312.5	250	MHz
T_{RX2}	RXUSRCLK2 maximum frequency	1 byte interface	376	376	312.5	250	MHz
		2 byte interface	406.25	406.25	312.5	250	MHz
		4 byte interface	206.25	206.25	156.25	125	MHz
T_{TX}	TXUSRCLK maximum frequency		412.5 ⁽³⁾	412.5 ⁽³⁾	312.5	250	MHz
T_{TX2}	TXUSRCLK2 maximum frequency	1 byte interface	376	376	312.5	250	MHz
		2 byte interface	406.25	406.25	312.5	250	MHz
		4 byte interface	206.25	206.25	156.25	125	MHz

Notes:

- Clocking must be implemented as described in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#).
- 406.25 MHz when the RX elastic buffer is bypassed.
- 406.25 MHz when the TX buffer is bypassed.

Table 24: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTXRX}	Serial data rate	RX oversampler not enabled	0.600	–	F _{GTXMAX}	Gb/s
		RX oversampler enabled	0.480	–	0.600	Gb/s
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		–	75	–	ns
RX _{OOBVDPP}	OOB detect threshold peak-to-peak		60	–	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	0	ppm
RX _{RL}	Run length (CID)	Internal AC capacitor bypassed	–	–	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance	CDR 2 nd -order loop disabled	–200	–	200	ppm
		CDR 2 nd -order loop enabled	–2000	–	2000	ppm
SJ Jitter Tolerance ⁽²⁾						
JT_SJ _{6.5}	Sinusoidal Jitter ⁽³⁾	6.5 Gb/s	0.44	–	–	UI
JT_SJ _{5.0}	Sinusoidal Jitter ⁽³⁾	5.0 Gb/s	0.44	–	–	UI
JT_SJ _{4.25}	Sinusoidal Jitter ⁽³⁾	4.25 Gb/s	0.44	–	–	UI
JT_SJ _{3.75}	Sinusoidal Jitter ⁽³⁾	3.75 Gb/s	0.44	–	–	UI
JT_SJ _{3.125}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s	0.45	–	–	UI
JT_SJ _{3.125L}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s ⁽⁴⁾	0.45	–	–	UI
JT_SJ _{2.5}	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s ⁽⁵⁾	0.5	–	–	UI
JT_SJ _{1.25}	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s ⁽⁶⁾	0.5	–	–	UI
JT_SJ ₆₀₀	Sinusoidal Jitter ⁽³⁾	600 Mb/s	0.4	–	–	UI
JT_SJ ₄₈₀	Sinusoidal Jitter ⁽³⁾	480 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye ⁽²⁾						
JT_TJSE _{3.125}	Total Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.70	–	–	UI
		5.0 Gb/s	0.70	–	–	UI
JT_SJSE _{3.125}	Sinusoidal Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.1	–	–	UI
		5.0 Gb/s	0.1	–	–	UI

Notes:

- Using PLL_RXDIVSEL_OUT = 1, 2, and 4.
- All jitter values are based on a bit error ratio of 1e^{–12}.
- The frequency of the injected sinusoidal jitter is 80 MHz.
- PLL frequency at 1.5625 GHz and OUTDIV = 1.
- PLL frequency at 2.5 GHz and OUTDIV = 2.
- PLL frequency at 2.5 GHz and OUTDIV = 4.
- Composite jitter with RX equalizer enabled. DFE disabled.

GTH Transceiver Switching Characteristics

Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further information.

Table 32: GTH Transceiver Maximum Data Rate and PLL Frequency Range

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate ⁽¹⁾	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

- Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	—	645	MHz
		-2 and -3 speed grades	150	—	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	—	—	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	—	—	20	μs

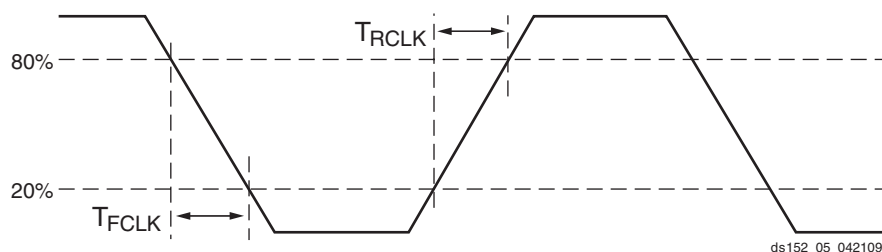


Figure 5: Reference Clock Timing Parameters

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
AV _{DD} = 2.5V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 5.2 MHz, T _j = -55°C to 125°C M-Grade, Typical values at T _j = +35°C						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	–	–	Bits
Integral Nonlinearity	INL		–	–	±1	LSBs
Differential Nonlinearity	DNL	No missing codes (T _{MIN} to T _{MAX}) Guaranteed Monotonic	–	–	±0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	–	±2	±30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	–	±2	±30	LSBs
Gain Error		Uncalibrated - External Reference	–	±0.2	±2	%
		Uncalibrated - Internal Reference	–	±2	–	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	–	±0.2	±2	%
		Uncalibrated - Internal Reference	–	±2	–	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	±10	–	LSBs
		Deviation from ideal transfer function. Internal reference	–	±20	–	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	±1	±2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	–	±0.01	–	LSB/°C
DC Common-Mode Reject	CMRR _{DC}	V _N = V _{CM} = 0.5V ± 0.5V, V _P – V _N = 100mV	–	70	–	dB
Conversion Rate⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	–	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	
T/H Acquisition Time	t _{ACQ}	Number of CLK cycles	4	–	–	
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	5.2	MHz
CLK Duty cycle			40	–	60	%

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns
LVC MOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns
LVC MOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns
LVC MOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns
LVC MOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns
LVC MOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns
LVC MOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns
LVC MOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns
LVC MOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns
LVC MOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns
LVC MOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns
LVC MOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns
LVC MOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVDCI_DV2_18	0.61	0.72	0.73	1.81	2.36	1.98	1.81	2.36	1.98	ns
LVDCI_DV2_15	0.73	0.85	0.85	1.77	2.30	1.98	1.77	2.30	1.98	ns
LVPECL_25	0.94	1.09	1.08	1.49	2.68	1.64	1.49	2.68	1.64	ns
HSTL_I_12	0.91	1.06	1.06	1.60	2.48	1.74	1.60	2.48	1.74	ns
HSTL_I_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns
HSTL_II_DCI	0.91	1.06	1.06	1.49	2.39	1.66	1.49	2.39	1.66	ns
HSTL_II_T_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns
HSTL_III_DCI	0.91	1.06	1.06	1.45	2.48	1.61	1.45	2.48	1.61	ns
HSTL_I_DCI_18	0.91	1.06	1.06	1.53	2.44	1.66	1.53	2.44	1.66	ns
HSTL_II_DCI_18	0.91	1.06	1.06	1.46	2.41	1.59	1.46	2.41	1.59	ns
HSTL_II_T_DCI_18	0.91	1.06	1.06	1.53	2.43	1.66	1.53	2.43	1.66	ns
HSTL_III_DCI_18	0.91	1.06	1.06	1.54	2.50	1.67	1.54	2.50	1.67	ns
DIFF_HSTL_I_18	0.94	1.09	1.08	1.58	2.30	1.72	1.58	2.30	1.72	ns
DIFF_HSTL_I_DCI_18	0.94	1.09	1.08	1.53	2.21	1.66	1.53	2.21	1.66	ns
DIFF_HSTL_I	0.94	1.09	1.08	1.56	2.28	1.71	1.56	2.28	1.71	ns
DIFF_HSTL_I_DCI	0.94	1.09	1.08	1.50	2.28	1.64	1.50	2.28	1.64	ns
DIFF_HSTL_II_18	0.94	1.09	1.08	1.62	2.33	1.78	1.62	2.33	1.78	ns
DIFF_HSTL_II_DCI_18	0.94	1.09	1.08	1.46	2.18	1.59	1.46	2.18	1.59	ns
DIFF_HSTL_II_T_DCI_18	0.94	1.09	1.08	1.53	2.22	1.66	1.53	2.22	1.66	ns
DIFF_HSTL_II	0.94	1.09	1.08	1.56	2.29	1.72	1.56	2.29	1.72	ns
DIFF_HSTL_II_DCI	0.94	1.09	1.08	1.49	2.26	1.66	1.49	2.26	1.66	ns
SSTL2_I_DCI	0.91	1.06	1.06	1.53	2.51	1.68	1.53	2.51	1.68	ns
SSTL2_II_DCI	0.91	1.06	1.06	1.50	2.50	1.69	1.50	2.50	1.69	ns
SSTL2_II_T_DCI	0.91	1.06	1.06	1.53	2.52	1.68	1.53	2.52	1.68	ns
SSTL18_I	0.91	1.06	1.06	1.58	2.48	1.73	1.58	2.48	1.73	ns
SSTL18_II	0.91	1.06	1.06	1.50	2.46	1.66	1.50	2.46	1.66	ns
SSTL18_I_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns
SSTL18_II_DCI	0.91	1.06	1.06	1.47	2.41	1.62	1.47	2.41	1.62	ns
SSTL18_II_T_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns
SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns
SSTL15_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns
DIFF_SSTL2_I	0.94	1.09	1.08	1.60	2.34	1.74	1.60	2.34	1.74	ns
DIFF_SSTL2_I_DCI	0.94	1.09	1.08	1.53	2.25	1.68	1.53	2.25	1.68	ns
DIFF_SSTL2_II	0.94	1.09	1.08	1.54	2.29	1.71	1.54	2.29	1.71	ns
DIFF_SSTL2_II_DCI	0.94	1.09	1.08	1.50	2.23	1.69	1.50	2.23	1.69	ns
DIFF_SSTL2_II_T_DCI	0.94	1.09	1.08	1.53	2.26	1.68	1.53	2.26	1.68	ns
DIFF_SSTL18_I	0.94	1.09	1.08	1.58	2.22	1.73	1.58	2.22	1.73	ns
DIFF_SSTL18_I_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 6 and Figure 7.

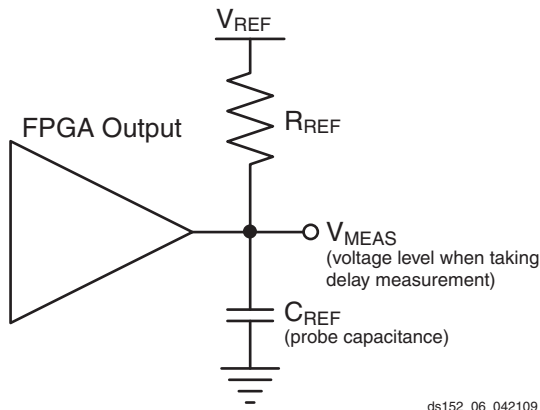
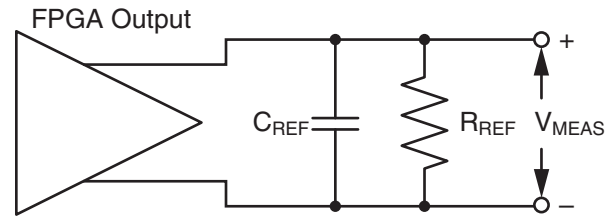


Figure 6: Single Ended Test Setup



ds152_07_042109

Figure 7: Differential Test Setup

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 48.
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 48: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R_{REF} (Ω)	$C_{REF}^{(1)}$ (pF)	V_{MEAS} (V)	V_{REF} (V)
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.2V	LVC MOS12	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25
SSTL, Class II, 2.5V	SSTL2_II	25	0	V_{REF}	1.25
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
LVDS EXT (LVDS Extended Mode), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
BLVDS (Bus LVDS), 2.5V	BLVDS_25	100	0	0 ⁽²⁾	0

Table 50: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{ODCK} /T _{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/ −0.08	0.50/ −0.08	0.54/ −0.08	0.54/ −0.08	0.69/ −0.11	ns
T _{OOCECK} /T _{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.17/ −0.03	0.20/ −0.03	0.22/ −0.03	0.27/ −0.05	0.27/ −0.04	ns
T _{OSRCK} /T _{OCKSR}	SR pin Setup/Hold with respect to CLK	0.59/ −0.24	0.62/ −0.24	0.54/ −0.08	0.54/ −0.08	0.79/ −0.35	ns
T _{OTCK} /T _{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.44/ −0.07	0.51/ −0.07	0.56/ −0.07	0.60/ −0.10	0.68/ −0.13	ns
T _{OTCECK} /T _{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.15/ −0.04	0.19/ −0.04	0.21/ −0.04	0.27/ −0.05	0.29/ −0.05	ns
Combinatorial							
T _{DOQ}	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
Sequential Delays							
T _{OCKQ}	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T _{RQ}	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T _{GSRQ}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
Set/Reset							
T _{RPW}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Input Serializer/Deserializer Switching Characteristics

Table 51: ISERDES Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold for Control Lines							
T _{ISCKK_BITSIP} / T _{ISCKC_BITSIP}	BITSLIP pin Setup/Hold with respect to CLKDIV	0.07/ 0.15	0.08/ 0.16	0.09/ 0.17	0.09/ 0.17	0.14/ 0.17	ns
T _{ISCKK_CE} / T _{ISCKC_CE} ⁽²⁾	CE pin Setup/Hold with respect to CLK (for CE1)	0.20/ 0.03	0.25/ 0.04	0.27/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T _{ISCKK_CE2} / T _{ISCKC_CE2} ⁽²⁾	CE pin Setup/Hold with respect to CLKDIV (for CE2)	0.01/ 0.27	0.01 0.29	0.01/ 0.31	0.01/ 0.31	−0.05/ 0.35	ns
Setup/Hold for Data Lines							
T _{ISDCK_D} / T _{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY) ⁽¹⁾	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin Setup/Hold with respect to CLK at DDR mode	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY) ⁽¹⁾	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
Sequential Delays							
T _{ISCKO_Q}	CLKDIV to out at Q pin	0.57	0.66	0.75	0.80	0.88	ns
Propagation Delays							
T _{ISDO_DO}	D input to DO output pin	0.19	0.22	0.25	0.25	0.28	ns

Notes:

- Recorded at 0 tap value.
- T_{ISCK_CE2} and T_{ISCK_CE2} are reported as $T_{ISCK_CE} / T_{ISCK_CE}$ in TRACE report.

Table 57: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T_{RCKK_WE}/T_{RCKC_WE}	Write Enable (WE) input (Block RAM only)	0.44/ 0.19	0.47/ 0.25	0.52/ 0.35	0.67/ 0.24	ns, Min
$T_{RCKK_WREN}/T_{RCKC_WREN}$	WREN FIFO inputs	0.47/ 0.26	0.50/ 0.27	0.55/ 0.30	0.68/ 0.31	ns, Min
$T_{RCKK_RDEN}/T_{RCKC_RDEN}$	RDEN FIFO inputs	0.46/ 0.26	0.50/ 0.27	0.55/ 0.30	0.67/ 0.31	ns, Min
Reset Delays						
T_{RCO_FLAGS}	Reset RST to FIFO Flags/Pointers ⁽¹⁰⁾	0.90	0.98	1.10	1.23	ns, Max
$T_{RCKK_RSTREG}/T_{RCKC_RSTREG}$	FIFO reset timing ⁽¹¹⁾	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
Maximum Frequency						
F_{MAX}	Block RAM in TDP and SDP modes (Write First and No Change modes)	600	540	450	340	MHz
	Block RAM (Read First mode)	525	475	400	275	MHz
	Block RAM (SDP mode) ⁽¹²⁾	525	475	400	275	MHz
$F_{MAX_CASCADE}$	Block RAM Cascade (Write First and No Change modes)	550	490	400	300	MHz
	Block RAM Cascade (Read First mode)	475	425	350	235	MHz
F_{MAX_FIFO}	FIFO in all modes	600	540	450	340	MHz
F_{MAX_ECC}	Block RAM and FIFO in ECC configuration	450	400	325	250	MHz

Notes:

- TRACE will report all of these parameters as T_{RCKO_DO} .
- T_{RCKO_DOR} includes T_{RCKO_DOW} , T_{RCKO_DOPR} , and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
- These parameters also apply to synchronous FIFO with $DO_REG = 0$.
- T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
- These parameters also apply to multirate (asynchronous) and synchronous FIFO with $DO_REG = 1$.
- T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY} , T_{RCKO_AFULL} , T_{RCKO_EMPTY} , T_{RCKO_FULL} , T_{RCKO_RDERR} , T_{RCKO_WRERR} .
- $T_{RCKO_POINTERS}$ includes both $T_{RCKO_RDCOUNT}$ and $T_{RCKO_WRCOUNT}$.
- The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
- T_{RCKO_DI} includes both A and B inputs as well as the parity inputs of A and B.
- T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
- The FIFO reset must be asserted for at least three positive clock edges.
- When using ISE software v12.4 or later, if the RDADDR_COLLISION_HWCONFIG attribute is set to PERFORMANCE or the block RAM is in single-port operation, then the faster F_{MAX} for WRITE_FIRST/NO_CHANGE modes apply.

DSP48E1 Switching Characteristics

Table 58: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}; B, \text{BCIN}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}; B, \text{BCIN}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{\text{DSPDCK}_{\text{C_CREG}}/T_{\text{DSPCKD}_{\text{C_CREG}}}}$	C input to C register CLK	0.16/ 0.20	0.19/ 0.22	0.22/ 0.24	0.25/ 0.24	0.33/ 0.30	ns
$T_{\text{DSPDCK}_{\text{D_DREG}}/T_{\text{DSPCKD}_{\text{D_DREG}}}}$	D input to D register CLK	0.07/ 0.31	0.10/ 0.34	0.15/ 0.39	0.16/ 0.39	0.24/ 0.45	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{MREG_MULT}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{MREG_MULT}}}$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{\text{DSPDCK}_{\{A, D\}}_{\text{ADREG}}/T_{\text{DSPCKD}_{\{A, D\}}_{\text{ADREG}}}$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG_MULT}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG_MULT}}}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ −0.13	4.37/ −0.13	5.20/ −0.13	5.20/ −0.13	5.94/ −0.24	ns
$T_{\text{DSPDCK}_{\text{D_PREG_MULT}}/T_{\text{DSPCKD}_{\text{D_PREG_MULT}}}}$	D input to P register CLK	3.62/ −0.47	4.13/ −0.47	4.90/ −0.47	4.90/ −0.47	5.61/ −0.77	ns
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG}}}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ −0.13	1.81/ −0.13	2.15/ −0.13	2.15/ −0.13	2.44/ −0.24	ns
$T_{\text{DSPDCK}_{\text{C_PREG}}/T_{\text{DSPCKD}_{\text{C_PREG}}}}$	C input to P register CLK	1.42/ −0.10	1.61/ −0.10	1.91/ −0.10	1.91/ −0.10	2.16/ −0.19	ns
$T_{\text{DSPDCK}_{\{\text{PCIN}, \text{CARRYCASCIN}, \text{MULTSIGNIN}\}}_{\text{PREG}}/T_{\text{DSPCKD}_{\{\text{PCIN}, \text{CARRYCASCIN}, \text{MULTSIGNIN}\}}_{\text{PREG}}}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ −0.02	1.41/ −0.02	1.67/ −0.02	1.67/ −0.02	1.91/ −0.07	ns
Setup and Hold Times of the CE Pins							
$T_{\text{DSPDCK}_{\{\text{CEA}; \text{CEB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{CEA}; \text{CEB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{\text{DSPDCK}_{\text{CEC_CREG}}/T_{\text{DSPCKD}_{\text{CEC_CREG}}}}$	CEC input to C register CLK	0.15/ 0.18	0.18/ 0.20	0.24/ 0.23	0.24/ 0.23	0.31/ 0.26	ns
$T_{\text{DSPDCK}_{\text{CED_DREG}}/T_{\text{DSPCKD}_{\text{CED_DREG}}}}$	CED input to D register CLK	0.20/ 0.12	0.24/ 0.13	0.31/ 0.14	0.31/ 0.14	0.43/ 0.16	ns
$T_{\text{DSPDCK}_{\text{CEM_MREG}}/T_{\text{DSPCKD}_{\text{CEM_MREG}}}}$	CEM input to M register CLK	0.16/ 0.19	0.20/ 0.21	0.26/ 0.25	0.26/ 0.25	0.32/ 0.28	ns
$T_{\text{DSPDCK}_{\text{CEP_PREG}}/T_{\text{DSPCKD}_{\text{CEP_PREG}}}}$	CEP input to P register CLK	0.32/ 0.02	0.38/ 0.02	0.46/ 0.03	0.46/ 0.03	0.54/ 0.04	ns
Setup and Hold Times of the RST Pins							
$T_{\text{DSPDCK}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{\text{DSPDCK}_{\text{RSTC_CREG}}/T_{\text{DSPCKD}_{\text{RSTC_CREG}}}}$	RSTC input to C register CLK	0.18/ 0.08	0.20/ 0.08	0.23/ 0.09	0.23/ 0.09	0.27/ 0.11	ns
$T_{\text{DSPDCK}_{\text{RSTD_DREG}}/T_{\text{DSPCKD}_{\text{RSTD_DREG}}}}$	RSTD input to D register CLK	0.28/ 0.15	0.32/ 0.16	0.38/ 0.19	0.38/ 0.19	0.45/ 0.21	ns
$T_{\text{DSPDCK}_{\text{RSTM_MREG}}/T_{\text{DSPCKD}_{\text{RSTM_MREG}}}}$	RSTM input to M register CLK	0.20/ 0.24	0.23/ 0.26	0.26/ 0.30	0.26/ 0.30	0.29/ 0.34	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Maximum Frequency							
F _{MAX}	With all registers used	600	540	450	450	410	MHz
F _{MAX_PATDET}	With pattern detector	551	483	408	408	356	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	356	311	262	262	224	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	327	286	241	241	211	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	398	347	292	292	254	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	398	347	292	292	254	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	266	233	196	196	171	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	250	219	184	184	160	MHz

Configuration Switching Characteristics

Table 59: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program Latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on-Reset	15/55	15/55	15/55	15/60	ms, Min/Max
T _{ICCK}	CCLK (output) delay	400	400	400	400	ns, Min
T _{PROGRAM}	Program Pulse Width	250	250	250	250	ns, Min
Master/Slave Serial Mode Programming Switching						
T _{DCCK} /T _{CCKD}	DIN Setup/Hold, slave mode	4.0/0.0	4.0/0.0	4.0/0.0	4.5/0.0	ns, Min
T _{DSCCK} /T _{SCCKD}	DIN Setup/Hold, master mode	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns, Min
T _{CCO}	DOUT at 2.5V	6	6	6	7	ns, Max
	DOUT at 1.8V	6	6	6	7	ns, Max
F _{MCCK}	Maximum CCLK frequency, serial modes	105	105	105	70	MHz, Max
F _{MCCKTOL}	Frequency Tolerance, master mode with respect to nominal CCLK.	55	55	55	60	%
F _{MSCCK}	Slave mode external CCLK	100	100	100	100	MHz
SelectMAP Mode Programming Switching						
T _{SMDCK} /T _{SMCKD}	SelectMAP Data Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCSCCK} /T _{SMCKCS}	CSI_B Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCCKW} /T _{SMWCK}	RDWR_B Setup/Hold	10.0/0.0	10.0/0.0	10.0/0.0	16.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	6	6	6	7	ns, Max
T _{SMCO}	CCLK to DATA out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to DATA out in readback at 1.8V	6	6	6	7	ns, Max

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$T_{\text{MMCMDCK_DI}}/$ $T_{\text{MMCCKD_DI}}$	DI Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
$T_{\text{MMCMDCK_DEN}}/$ $T_{\text{MMCCKD_DEN}}$	DEN Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
$T_{\text{MMCMDCK_DWE}}/$ $T_{\text{MMCCKD_DWE}}$	DWE Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
$T_{\text{MMCCKO_DO}}$	CLK to out of DO ⁽³⁾	2.60	3.02	3.64	3.68	ns
$T_{\text{MMCCKO_DRDY}}$	CLK to out of DRDY	0.32	0.34	0.38	0.38	ns

Notes:

1. To support longer delays in configuration, use the design solutions described in [UG360: Virtex-6 FPGA Configuration User Guide](#).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.
3. DO will hold until next DRP operation.

Clock Buffers and Networks

Table 60: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Devices	Speed Grade				Units
			-3	-2	-1	-1L	
$T_{\text{BCCCK_CE}}/T_{\text{BCCCK_CE}}^{(1)}$	CE pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
$T_{\text{BCCCK_S}}/T_{\text{BCCCK_S}}^{(1)}$	S pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
$T_{\text{BCKO_O}}^{(2)}$	BUFGCTRL delay from I0/I1 to O	All	0.07	0.08	0.10	0.10	ns
Maximum Frequency							
F_{MAX}	Global clock tree (BUFG)	All except LX760	800	750	700	667	MHz
		LX760	N/A	700	700	667	MHz

Notes:

1. $T_{\text{BCCCK_CE}}$ and $T_{\text{BCCCK_S}}$ must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX_VIRTEX4 primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. $T_{\text{BCKO_O}}$ (BUFG delay from I0 to O) values are the same as $T_{\text{BCKO_O}}$ values.

Table 61: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$T_{\text{BIOCKO_O}}$	Clock to out delay from I to O	0.14	0.16	0.18	0.21	ns
Maximum Frequency						
F_{MAX}	I/O clock tree (BUFIO)	800	800	710	710	MHz

Table 62: Regional Clock Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$T_{\text{BRCKO_O}}$	Clock to out delay from I to O	0.56	0.62	0.73	0.82	ns
$T_{\text{BRCKO_O_BYP}}$	Clock to out delay from I to O with Divide Bypass attribute set	0.28	0.31	0.36	0.41	ns

Clock Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-6 FPGA clock transmitter and receiver data-valid windows.

Table 71: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽¹⁾	All	0.12	0.12	0.12	0.12	ns
T_{CKSKEW}	Global Clock Tree Skew ⁽²⁾	XC6VLX75T	0.15	0.16	0.18	0.17	ns
		XC6VLX130T	0.25	0.26	0.29	0.28	ns
		XC6VLX195T	0.26	0.27	0.31	0.30	ns
		XC6VLX240T	0.26	0.27	0.31	0.30	ns
		XC6VLX365T	0.28	0.29	0.31	0.31	ns
		XC6VLX550T	N/A	0.50	0.54	0.54	ns
		XC6VLX760	N/A	0.51	0.56	0.56	ns
		XC6VSX315T	0.27	0.28	0.32	0.30	ns
		XC6VSX475T	N/A	0.39	0.44	0.42	ns
		XC6VHX250T	0.25	0.26	0.29	N/A	ns
		XC6VHX255T	0.35	0.37	0.41	N/A	ns
		XC6VHX380T	0.45	0.47	0.52	N/A	ns
		XC6VHX565T	N/A	0.46	0.51	N/A	ns
		XQ6VLX130T	N/A	0.26	0.29	0.28	ns
		XQ6VLX240T	N/A	0.27	0.31	0.30	ns
		XQ6VLX550T	N/A	N/A	0.54	0.54	ns
		XQ6VSX315T	N/A	0.28	0.32	0.30	ns
		XQ6VSX475T	N/A	N/A	0.44	0.42	ns
T_{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.08	0.08	0.08	0.08	ns
T_{BUFIO_SKEW}	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.02	ns
T_{BUFIO_SKEW2}	I/O clock tree skew across three clock regions	All	0.10	0.12	0.23	0.12	ns
T_{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

- These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
- The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

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